

<b>Notice of References Cited</b>	Application/Control No. 09/823,195	Applicant(s)/Patent Under Reexamination ZHANG ET AL.	
	Examiner Caridad M. Everhart	Art Unit 2891	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0190429	09-2004	McCreery, Richard L.	369/126
	B	US-			
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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